Record Nr. UNINA9910455567803321 Advanced high speed devices [[electronic resource] /] / editors, Michael **Titolo** S. Shur, Paul Maki Pubbl/distr/stampa Hackensack, N.J.,: World Scientific, 2010 **ISBN** 1-282-76159-5 9786612761591 981-4287-87-3 Descrizione fisica 1 online resource (203 p.) Collana Selected topics in electronics and systems;; v. 51 Altri autori (Persone) ShurMichael S MakiPaul Disciplina 621.3815 Soggetti Very high speed integrated circuits Semiconductors **Transistors** Integrated circuits - Very large scale integration Electronic books. Lingua di pubblicazione Inglese **Formato** Materiale a stampa Livello bibliografico Monografia Note generali "This volume contains the proceedings of the 2008 biennial Lester Eastman Conference (LEC), which was held on the Cornell University of Delaware campus on August 5-7, 2008. Conference was known as IEEE/Cornell University Confernce on High Performance Devices."--Preface. Includes bibliographical references. Nota di bibliografia Nota di contenuto CONTENTS; Preface; Simulation and Experimental Results on GaN Based Ultra-Short Planar Negative Di.erential Conductivity Diodes for THz Power Generation B. Aslan, L. F. Eastman and Q. Diduck; 1. Introduction; 2. Simulation Results; 3. Experimental results and discussion; 4. Conclusion; References; 5-Terminal THz GaN Based Transistor with Field- and Space-Charge Control Electrodes G. Simin. M. S. Shur and R. Gaska; 1. Introduction; 2. GaN Heterostructure Field-Effect Transistors; 3. Proposed novel five-terminal GaN based THz HFET; 4. Acknowledgement; References Performance Comparison of Scaled III-V and Si Ballistic Nanowire

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Sommario/riassunto

Advanced High Speed Devices covers five areas of advanced device technology: terahertz and high speed electronics, ultraviolet emitters and detectors, advanced III-V field effect transistors, III-N materials and devices, and SiC devices. These emerging areas have attracted a lot of attention and the up-to-date results presented in the book will be of interest to most device and electronics engineers and scientists. The contributors range from prominent academics, such as Professor Lester Eastman, to key US Government scientists, such as Dr Michael Wraback.